

Effect of Substrate Composition on Sn Whisker Growth in Pure Sn Films

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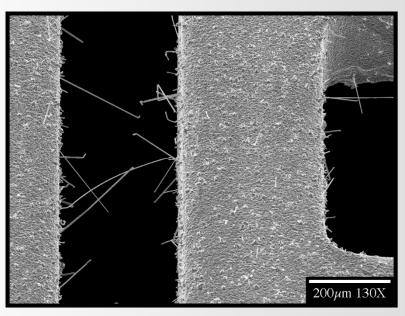


Overview

- Introduction
- Experimental Procedures
- Results & Discussions
- Conclusions
- Acknowledgments

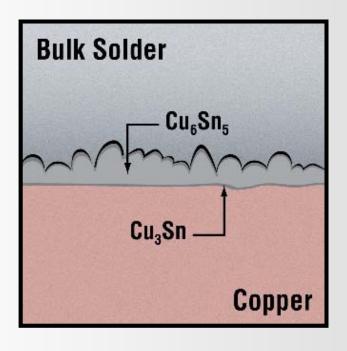
Introduction

- Sn as solder material
 - Prone to whiskers
 - -Alloyed with Pb
 - -RoHS Legislation, 2003
- Whisker growth mechanism
 - -IMC formation, Cu₆Sn₅, resulting in compressive stresses
 - Formation by diffusion of Cu in Sn grain boundaries



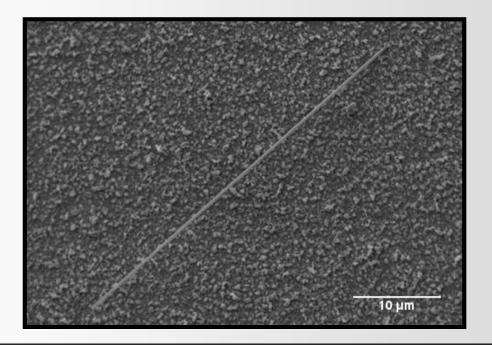
Introduction

- Whisker suppression
 - -Post-baking procedures
 - Tensile vs. Compressive stresses
 - IMC type
 - -Ni barrier layer
 - Prevents diffusion of Cu



Introduction

- Current study
 - -Scope: Effect of substrate composition on tin whisker growth
 - Objective: Determine effect of including Zn in substrate



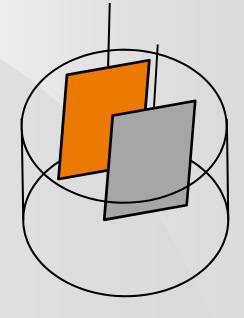
Experimental Procedures

Substrate materials

- -Pure Cu
- 70% Cu 30% Zn (brass)

Pre-electroplating preparation

- -Grinding, polishing
- -Cleaning in heated sodium hydroxide
- Dipping in concentrated sulfuric acid
- Alkaline electrolyte
 - -142.096 g sodium tin (IV) oxide per liter solution
 - -14.960 g sodium hydroxide per liter solution.
- Plating parameters
 - -1 µm or 10 µm thick Sn layer
 - 50 mA/cm² current density
 - -85°C to 95°C bath temperature

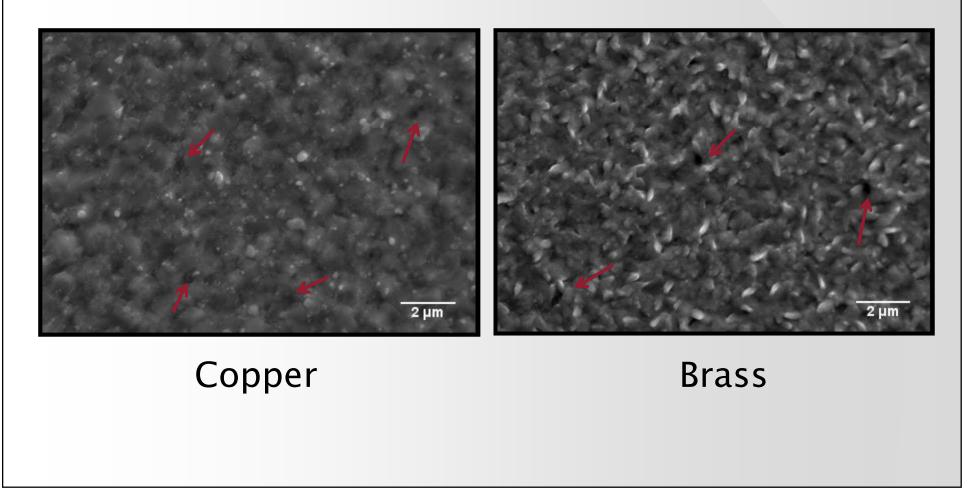


Experimental Procedures

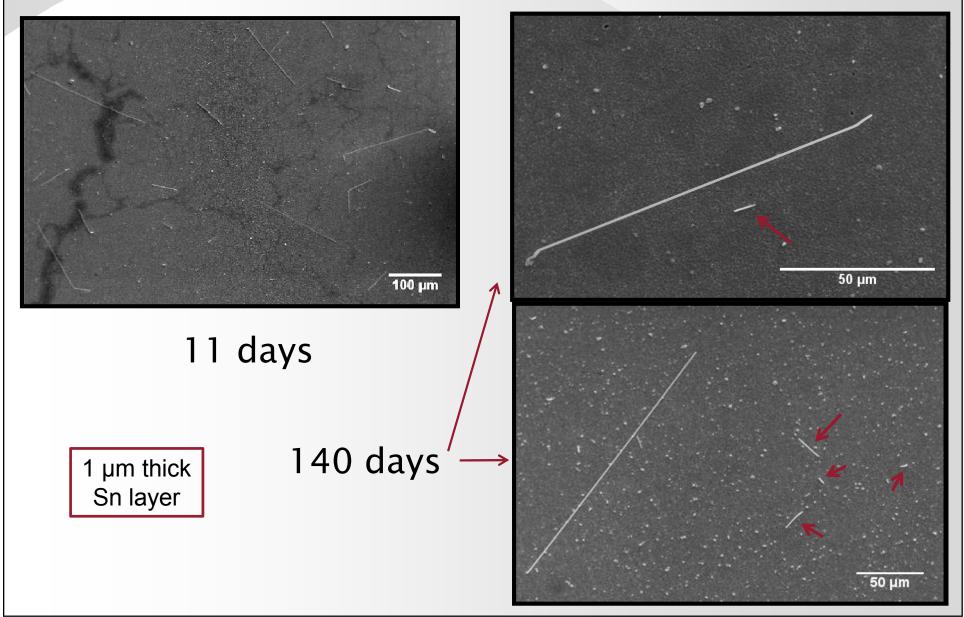
- Aged at RT in air
- Equipment:
 - FESEM for imaging
 - EDM for cross-sectioning
 - EDS for composition

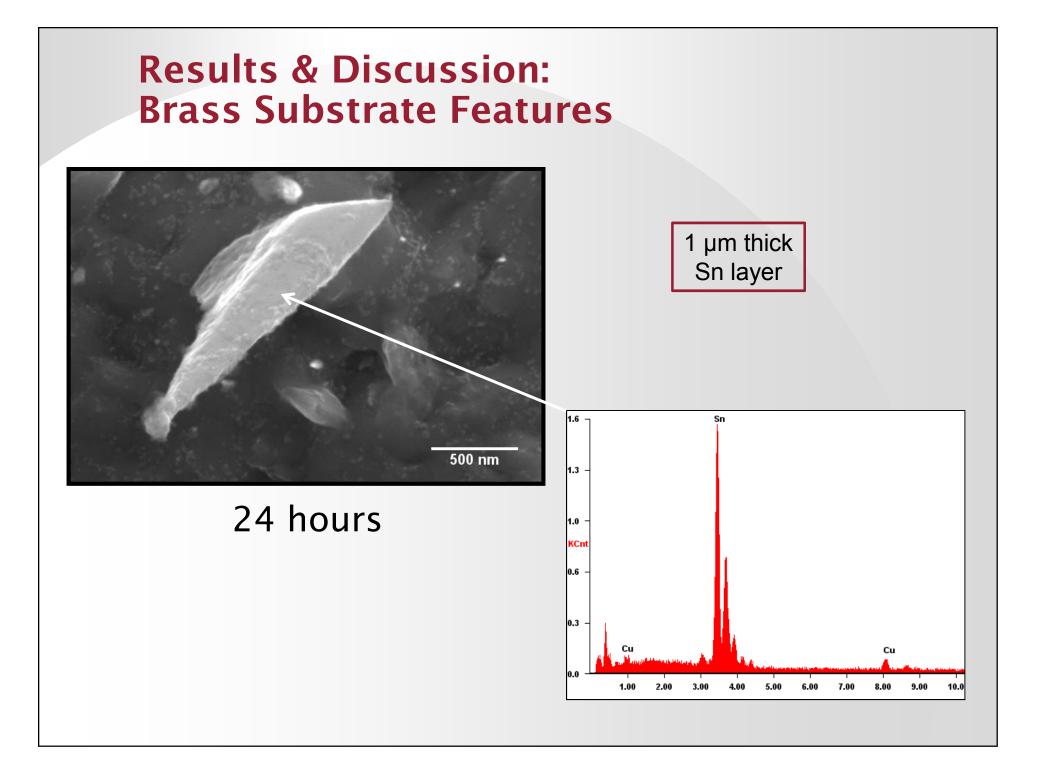
Results & Discussion: Comparing Surface Morphology

• 1 µm thick Sn layers (24 hrs after plating)



Results & Discussion: Cu Substrate Features

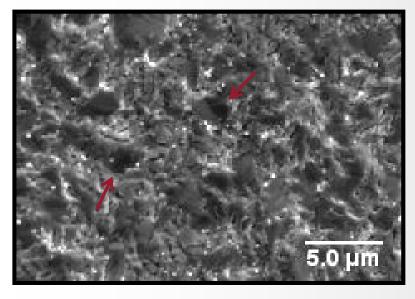


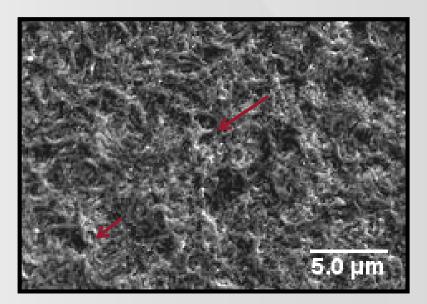


Results & Discussion: Comparing Surface Morphology

•10 µm thick Sn layers

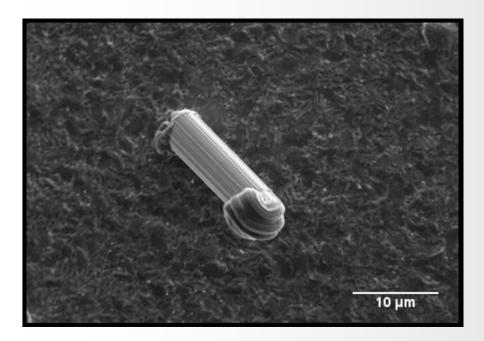
Copper





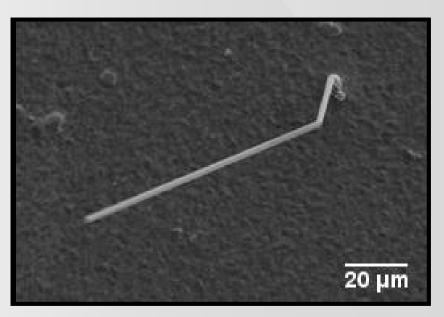
Brass

Results & Discussion: Cu Substrate Features



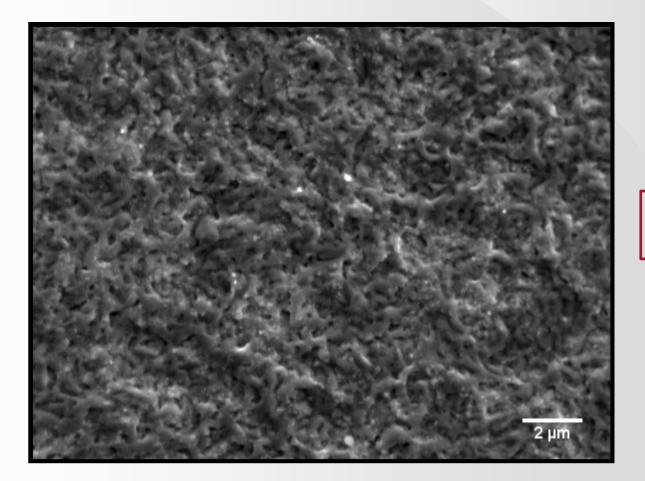
21 days

10 µm thick Sn layer



28 days

Results & Discussion: Brass Substrate Features



10 µm thick Sn layer

57 days

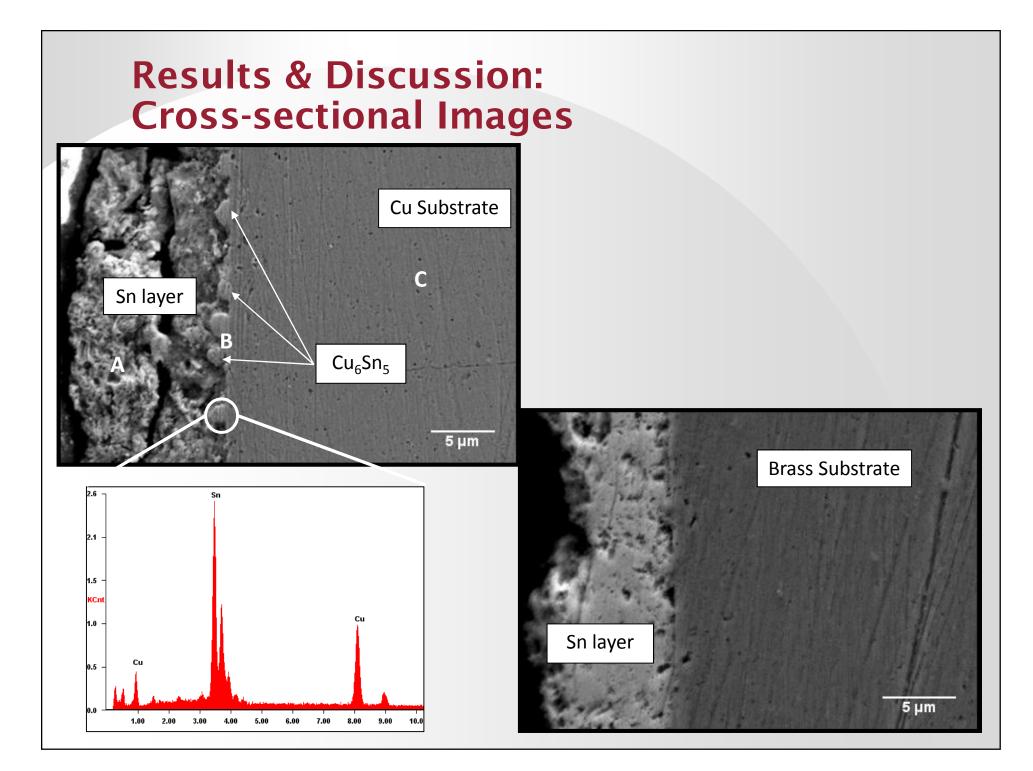
Results & Discussion: Specific Molar Volume Values for IMCs

IMC	Molar weight	Density	Molar volume
	(g/mol)	(g/cm^3)	(cm ³ /mol)
Sn	118.71	7.365	16.23
Cu_6Sn_5	974.69	8.28	117.71
Cu ₃ Sn	309.31	8.9	34.75
Cu_5Zn_8	840.74	7.98	105.35

Results & Discussion: Energy of Formation Values: Cu/Sn & Cu/Sn/Zn Systems

IMC	X _{cu}	ΔH	ΔS	ΔG at 298 K
		(kJ/mol)	(J/mol*K)	(kJ/mol)
Cu_5Zn_8	0.4	-11.41	1.62	-11.89
CuZn	0.5	-11.12	0.69	-11.33
Cu ₃ Sn	0.7	-3.91	6.75	-5.75
Cu ₃ Sn	0.8	-4.10	5.55	-5.92
Cu_6Sn_5	0.6	-2.99	7.73	-5.29
Cu_6Sn_5	0.5	-1.99	8.05	-4.39

•Cu-Zn IMCs more thermodynamically favorable in Sn-Cu-Zn system



Conclusions

<u>Cu Substrate</u>

- Whiskers observed
- IMC formation

Brass Substrate

- No whiskers observed
- No IMC formation

 Including Zn at Sn-Cu interface can mitigate growth of Sn whiskers

•Future Work: Plate pure copper with two layers

•Zn & Sn

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